

Form PTO-1449 (Substitute) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)	Attorney Docket Number ANRI-08064US1	Application Number New Application 10/641,700
	Applicant Jon S. Martens et al.	
	Filing Date August 15, 2003	Group Art Unit 2863 New Application

U.S. PATENTS

Examiner Initial		Patent Number	Issue Date	First Named Inventor	Class	Subclass	Filing Date
FL	1	5,578,932 A	11/26/96	Adamian	324	601	06/07/95
↓	2	5,748,506 A	05/05/98	Bockelman	702	85	05/28/96
↓	3	6,188,968 A	02/13/01	Blackham	702	85	05/18/98
↓	4	6,300,775 A	10/09/01	Peach, et al.	324	601	02/02/99

OTHER DOCUMENTS (Include author (if any), title, publisher and place of publication, date and pertinent pages)

FL	5	Anritsu Model 360B Vector Network Analyzer, Operation Manual, Revision F, Chapters 3, 4, 5, 6, 7, 8 and 9, Pages 3-4 to 9-46, October 1997
↓	6	Anritsu Application Note, Reflectometer Measurements - Revisited, Rev. C, 12 pages, April 2000,
↓	7	Bauer, R.F. et al., "De-Embedding and Unterminating," IEEE Transactions of Microwave Theory and Technique, Vol. MTT-22, No. 3, Pages 282- 288, March 1974
↓	8	Daywitt, W.C., "Determining Adapter Efficiency by Envelope Averaging Swept Frequency Reflection Data," IEEE Transactions on Microwave Theory and Techniques, Vol. 38, No. 11, Pages 1748 - 1752, November 1990
↓	9	Eberly, Mike et al., "Intro to the Agilent 8714 - RF Network Analyzer," Agilent Technologies, EducatorsCorner.com, Experiments, 7 pages, Date Unknown
FL	10	Edwards, M.L., "Calibration and Measurements of S-Parameters," <u>Microwave & RF Circuits: Analysis, Design, Fabrication & Measurement</u> , Chapter 7, 23 pages, September 2001
↓	11	Fay, P. "Error Correction For Network Analysis - Lab #5," Microwave Circuit Design and Measurements Lab, EE 458/558, 3 pages, Revised 9/2001
↓	12	Glasser, L.A., "An Analysis of Microwave De-embedding Errors," IEEE Transactions on Microwave Theory and Techniques, Vol. MTT-26, No. 5, Pages 379 - 380, May 1978
↓	13	Gonzalez, G., <u>Microwave Transistor Amplifiers, Analysis and Design</u> , Prentice-Hall, Inc., New Jersey, Chapters 1 and 2, Pages 1 - 90, August 1996
↓	14	King, J.D. et al., "Direct Characterization of Non-Insertable Microwave Test Fixtures For Packaged MMICs," in 57 th ARFTG Conf. Digest, pp. 19-27, May 2001
↓	15	Matthew, P.J. et al., "RF Impedance Measurement Calibration," http://www.aps.anl.gov/techpub/lsnotes/ls223/ls223.html , 16 pages, February 12, 1993

OTHER DOCUMENTS (Include author (if any), title, publisher and place of publication, date and pertinent pages)		
FL	16	Nelson, R., "What are S-parameters, anyway?," Test & Measurement World, http://www.tmworld.com/articles/2001/02_sparameters.htm , 9 pages, February 2001
	17	"Network Analyser Calibration," http://www.morph.demon.co.uk/Electronics/new.htm , 12 pages, visited November 13, 2001
	18	Pollard, R.D. et al., "The Calibration Of A Universal Test Fixture," 1983 MIT-S Digest, Pages 498 - 500 (year of publication is sufficiently earlier than the effective U.S. filing date and any foreign priority date so that the particular month of publication is not at issue, in accordance with MPEP §609.III.A.)
	19	Product Note, Aglient 8510-13, "Measuring Noninsertable Devices," Agilent Technologies, 15 pages, August 1988
	20	Randa, J. et al., "Comparison of Adapter Characterization Methods," IEEE Transactions on Microwave Theory and Techniques, Vol. 47, pp. 2613-2620, December 1999
	21	Silvonen, K., "Calibration and De-Embedding of Microwave Measurements Using Any Combination of One-or Two-Port Standards, Circuit Theory Laboratory CT-4, Helsinki University of Technology, 28 pages, December 1987
	22	Tippet, J.C. et al., "A Rigorous Technique for Measuring the Scattering Matrix of a Multiport Device with a 2-Port Network Analyzer," IEEE Transactions on Microwave Theory and Techniques, Vol. MTT-30, No. 5, pp. 661-666, May 1992
	23	Vaitkus, R. et al., "A Two-Tier Deembedding Technique For Packaged Transistors," 1982 IEEE MTT-S Digest, Pages 328-330 (year of publication is sufficiently earlier than the effective U.S. filing date and any foreign priority date so that the particular month of publication is not at issue, in accordance with MPEP §609.III.A.)
	24	Wiatr, W., "A Method for Embedding Network Characterization with Application to Low-Loss Measurements," IEEE Transactions on Instruments and Measurement, Vol. IM-36, No. 2, pp. 487-490, June 1987
	25	Williams, D.F. et al., "In-Line Multiport Calibration Algorithm," in 51st ARFTG Conf. Digest, pp. 88-90, June 12, 1998
	26	Willron/Anritsu Company, Documentation for the 360B and 37xxx Network Analyzers, pp. 8-34 to 8-38, Date Unknown
FL	27	Ferrero, A. "A Simplified Algorithm for Leakey Network Analyzer Calibration," IEEE Microwave and Guided Wave Letters, Vol. 5, No. 4, pp. 119-121, April 1995
	28	Speciale, Ross A., "A Generalization of TSD Network-Analyzer Calibration Procedure, Covering n -Port Scattering-Parameter Measurements, Affected by Leakage Errors," IEEE Transactions on Microwave and Techniques, Vol. MIT-25, No. 12, pp. 1100-1115, December 1977
Examiner <i>John Se</i>		Date Considered <i>01/07/05</i>
<p>*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p> <p>*1 = Copy not submitted because it was submitted in prior application SN <u> </u> / <u> </u>, filed <u> </u>, 20<u> </u>, relied on under 35 USC §120.</p> <p>*2 = Copy not submitted because it was submitted in prior application SN <u> </u> / <u> </u>, filed <u> </u>, 20<u> </u>, relied on under 35 USC §120.</p>		